UTC UNISONIC TECHNOLOGIES CO., LTD

2N50 **Preliminary Power MOSFET**

N-CHANNEL 2A, 500V **POWER MOSFET**

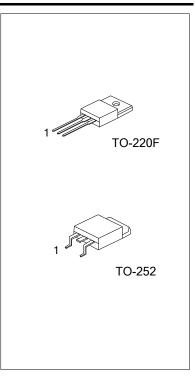
DESCRIPTION

The UTC 2N50 is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

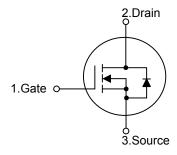
The UTC 2N50 is generally applied in high efficiency switch mode power supplies, active power factor correction and electronic lamp ballasts based on half bridge topology.

FEATURES

- * $R_{DS(ON)}$ = 4.9 Ω @ V_{GS} =10V
- * High Switching Speed
- * 100% Avalanche Tested



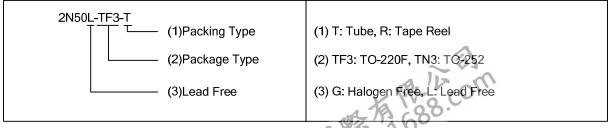
SYMBOL



ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
2N50L-TF3-T	2N50G-TF3-T	TO-220F	G	D	S	Tube	
2N50L-TN3-R	2N50G-TN3-R	TO-252	G	D	S	Tape Reel	

S: Source Pin Assignment: G: Gate D: Drain



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■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARA	METER	SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	500	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous (T _C =25°	C) I _D	2 (Note 3)	Α	
Drain Current	Pulsed (Note 2)	I _{DM}	8 (Note 3)	Α	
Avalanche Current (Not	e 2)	I _{AR}	2	Α	
Avalancha Energy	Single Pulsed	E _{AS}	82	mJ	
Avalanche Energy	Repetitive (Note 4)	E _{AR}	3.3	mJ	
TO-220F			23	10/	
Power Dissipation (T _C =	TO-252		50	W	
TO-22		P _D	0.18	14//90	
Derate above 25°C	TO-252		0.4	W/°C	
Junction Temperature	·	TJ	+150	°C	
Storage Temperature		T _{STG}	-55~+150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. Drain current limited by maximum junction temperature
- 4. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT	
lunation to Ambient	TO-220F	0	62.5	°C/W	
Junction to Ambient	TO-252	θ_{JA}	110		
lunation to Coop	TO-220F	θ_{JC}	5.5	°C/W	
Junction to Case	TO-252		2.5		



ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise noted)

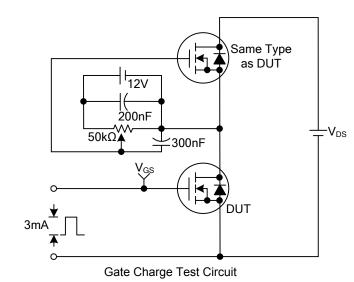
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V				V			
Drain-Source Leakage Current	I _{DSS}	V _{DS} =500V, V _{GS} =0V			25	μA			
Coto Source Leakage Current Forward	I _{GSS}	V_{GS} =+30V, V_{DS} =0V			+100	nA			
Gate- Source Leakage Current Reverse		V_{GS} =-30V, V_{DS} =0V			-100	nA			
ON CHARACTERISTICS									
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$			4.0	V			
Static Drain-Source On-State Resistance	R _{DS(ON)}	V_{GS} =10V, I_D =1A		3.9	4.9	Ω			
DYNAMIC PARAMETERS									
Input Capacitance	C _{ISS}	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		236		pF			
Output Capacitance	Coss			40		pF			
Reverse Transfer Capacitance	C_{RSS}			22		pF			
SWITCHING PARAMETERS									
Total Gate Charge	Q_{G}	-V _{GS} =10V, V _{DS} =400V, I _D =2A -(Note 1, 2)		20	25	nC			
Gate to Source Charge	Q_{GS}			2	3	nC			
Gate to Drain Charge	Q_{GD}			12	15	nC			
Turn-ON Delay Time	t _{D(ON)}			10		ns			
Rise Time	t _R	V_{DD} =250V, I_{D} =2A, R_{G} =25Ω (Note 1, 2)		20		ns			
Turn-OFF Delay Time	t _{D(OFF)}			60		ns			
Fall-Time	t _F			20		ns			
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS									
Maximum Body-Diode Continuous Current	I _S				2	Α			
Maximum Body-Diode Pulsed Current	I _{SM}				8	Α			
Drain-Source Diode Forward Voltage	V _{SD}	I _S =2A, V _{GS} =0V			1.2	V			
Body Diode Reverse Recovery Time	t _{RR}	I _S =2A, V _{GS} =0V, dI _F /dt=100A/μs		300		ns			
Body Diode Reverse Recovery Charge	Q_{RR}	(Note 1)		2.1		μC			

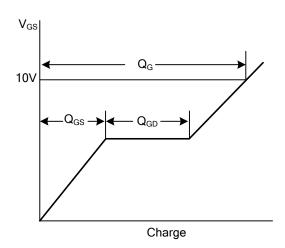
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%



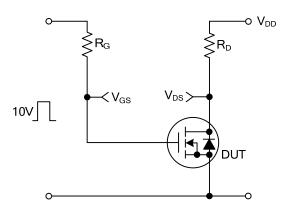
^{2.} Essentially independent of operating temperature

TEST CIRCUITS AND WAVEFORMS

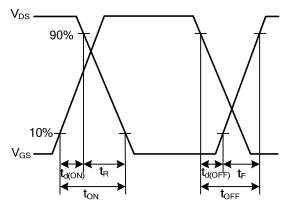




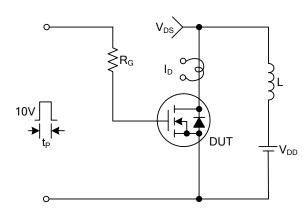
Gate Charge Waveforms



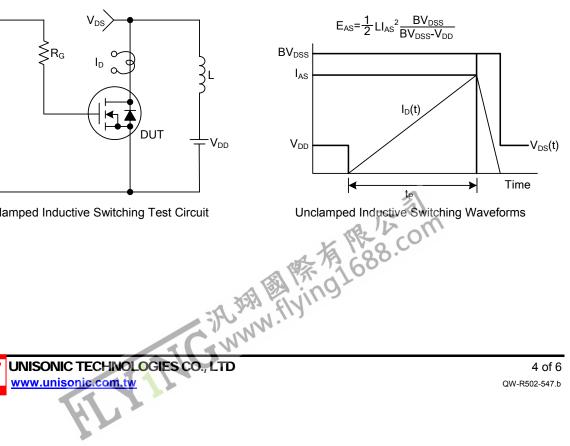
Resistive Switching Test Circuit



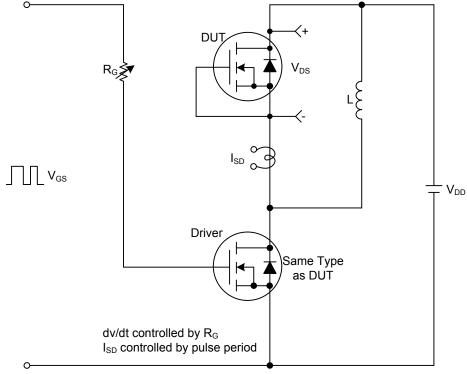
Resistive Switching Waveforms



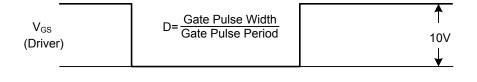
Unclamped Inductive Switching Test Circuit

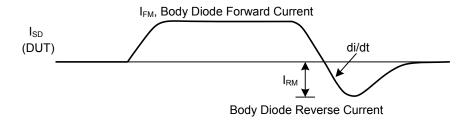


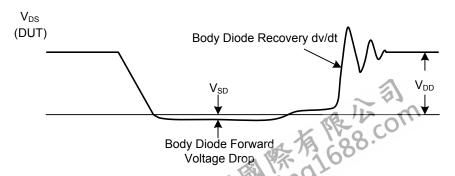
■ TEST CIRCUITS AND WAVEFORMS(Cont.)



Peak Diode Recovery dv/dt Test Circuit & Waveforms







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